

# N-channel TrenchMOS standard level FET Rev. 02 — 26 January 2011

Product data sheet

Suitable for standard level gate drive

Suitable for thermally demanding environments due to 175 °C rating

Motors, lamps and solenoids

sources

#### **Product profile** 1.

#### 1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

#### 1.2 Features and benefits

- AEC Q101 compliant
- Low conduction losses due to low on-state resistance
- 1.3 Applications
  - 12 V and 24 V loads
  - Automotive and general purpose power switching

### 1.4 Quick reference data

#### Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	-	55	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 10 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	18	A
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	-	51	W
Static cha	racteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS}$ = 10 V; $I_D$ = 10 A; $T_j$ = 175 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	-	154	mΩ
		$V_{GS} = 10 \text{ V}; I_D = 10 \text{ A};$ T <sub>j</sub> = 25 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	65	77	mΩ
Avalanche	e ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\begin{split} I_D &= 6 \text{ A};  V_{sup} \leq 55 \text{ V}; \\ R_{GS} &= 50  \Omega;  V_{GS} = 10 \text{ V}; \\ T_{j(\text{init})} &= 25 ^\circ\text{C}; \text{ unclamped} \end{split}$	-	-	36	mJ



#### N-channel TrenchMOS standard level FET

### 2. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		-
2	D	drain	mb	D
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S
			SOT428 (DPAK)	

### 3. Ordering information

Table 3. Ordering information						
Type number	Package					
	Name	Description	Version			
BUK7277-55A	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428			

### 4. Limiting values

#### Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

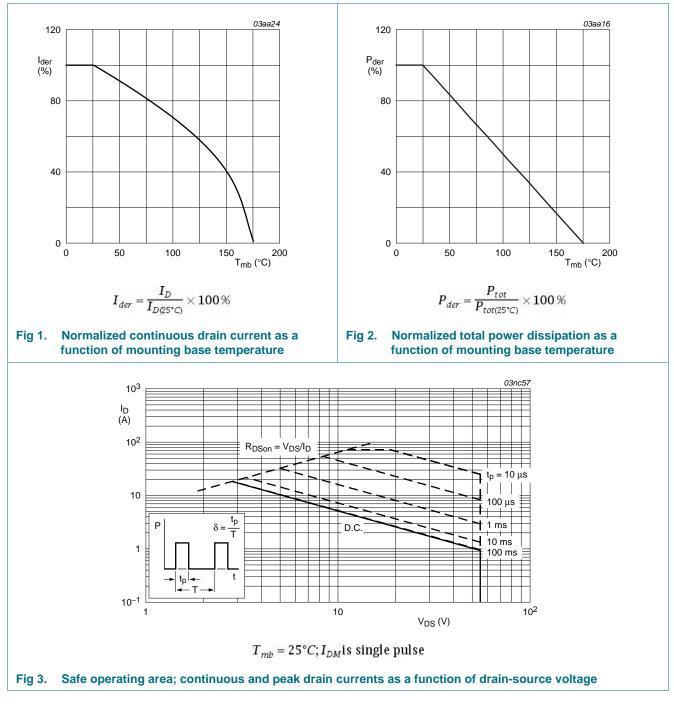
Parameter	Conditions		Min	Max	Unit
drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	55	V
drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$		-	55	V
gate-source voltage			-20	20	V
drain current	$T_{mb}$ = 100 °C; $V_{GS}$ = 10 V; see <u>Figure 1</u>		-	13	А
	$T_{mb} = 25 \text{ °C}; V_{GS} = 10 \text{ V}; \text{ see } \frac{\text{Figure 1}}{\text{Figure 3}};$		-	18	А
peak drain current	$T_{mb} = 25 \text{ °C}; \text{ pulsed}; t_p \le 10 \mu\text{s}; $ see Figure 3	1	-	73	А
total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>		-	51	W
storage temperature			-55	175	°C
junction temperature			-55	175	°C
diode					
source current	T <sub>mb</sub> = 25 °C		-	18	А
peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^{\circ}C$		-	73	А
ggedness					
non-repetitive drain-source avalanche energy	I <sub>D</sub> = 6 A; V <sub>sup</sub> ≤ 55 V; R <sub>GS</sub> = 50 Ω; V <sub>GS</sub> = 10 V; T <sub>i(init)</sub> = 25 °C; unclamped		-	36	mJ
	drain-source voltage drain-gate voltage gate-source voltage drain current peak drain current total power dissipation storage temperature junction temperature diode source current peak source current ggedness non-repetitive drain-source	$\begin{array}{ll} \text{drain-source voltage} & \text{T}_{j} \geq 25 \ ^{\circ}\text{C}; \ \text{T}_{j} \leq 175 \ ^{\circ}\text{C} \\ \text{drain-gate voltage} & \text{R}_{GS} = 20 \ \text{k}\Omega \\ \text{gate-source voltage} \\ \text{drain current} & \frac{\text{T}_{mb} = 100 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see Figure 1}}{\text{T}_{mb} = 25 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see Figure 1}}; \\ \text{see Figure 3} \\ \text{peak drain current} & \text{T}_{mb} = 25 \ ^{\circ}\text{C}; \ \text{pulsed}; \ \text{t}_{p} \leq 10 \ \text{\mu}\text{s}; \ \begin{array}{c} \text{I} \\ \text{see Figure 3} \\ \text{storage temperature} \\ \text{junction temperature} \\ \text{junction temperature} \\ \text{diode} \\ \text{source current} & \text{T}_{mb} = 25 \ ^{\circ}\text{C} \\ \text{peak source current} & \text{T}_{mb} = 25 \ ^{\circ}\text{C} \\ \text{peak source current} & \text{pulsed}; \ \text{t}_{p} \leq 10 \ \text{\mu}\text{s}; \ \text{T}_{mb} = 25 \ ^{\circ}\text{C} \\ \text{ggedness} \\ \text{non-repetitive drain-source} & \text{I}_{D} = 6 \ \text{A}; \ \text{V}_{sup} \leq 55 \ \text{V}; \ \text{R}_{GS} = 50 \ \Omega; \\ \end{array}$	$\begin{array}{ll} drain-source \ voltage & T_{j} \geq 25 \ ^{\circ}\text{C}; \ T_{j} \leq 175 \ ^{\circ}\text{C} \\ drain-gate \ voltage & R_{GS} = 20 \ \text{k}\Omega \\ \\ gate-source \ voltage & \\ drain \ current & \frac{T_{mb} = 100 \ ^{\circ}\text{C}; \ V_{GS} = 10 \ \text{V}; \ \text{see Figure 1}}{T_{mb} = 25 \ ^{\circ}\text{C}; \ V_{GS} = 10 \ \text{V}; \ \text{see Figure 1}}; \\ \\ see \ Figure \ 3 & \\ total \ power \ dissipation & T_{mb} = 25 \ ^{\circ}\text{C}; \ pulsed; \ t_{p} \leq 10 \ \mu\text{s}; \ \ 11 \\ \\ \text{see Figure 3} & \\ total \ power \ dissipation & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see Figure 2} & \\ \\ storage \ temperature & \\ \\ \hline \textbf{diode} & \\ \\ \text{source \ current} & T_{mb} = 25 \ ^{\circ}\text{C} \\ \\ peak \ source \ current & T_{mb} = 25 \ ^{\circ}\text{C} \\ \\ peak \ source \ current & pulsed; \ t_{p} \leq 10 \ \mu\text{s}; \ T_{mb} = 25 \ ^{\circ}\text{C} \\ \\ \hline \textbf{ggedness} & \\ \\ \text{non-repetitive \ drain-source} & I_{D} = 6 \ \text{A}; \ V_{sup} \leq 55 \ \text{V}; \ R_{GS} = 50 \ \Omega; \\ \end{array}$	$\begin{array}{cccc} drain-source voltage & T_j \geq 25 \ ^{\circ}\text{C}; \ T_j \leq 175 \ ^{\circ}\text{C} & - \\ \\ drain-gate voltage & R_{GS} = 20 \ \text{k}\Omega & - \\ \\ gate-source voltage & -20 \\ \\ drain current & T_{mb} = 100 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see Figure 1} & - \\ \\ \hline T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{V}_{GS} = 10 \ \text{V}; \ \text{see Figure 1}; \\ \text{see Figure 3} & - \\ \\ peak \ drain \ current & T_{mb} = 25 \ ^{\circ}\text{C}; \ pulsed; \ t_p \leq 10 \ \mu\text{s}; \ \ \ 11 & - \\ \\ \text{see Figure 3} & - \\ \\ \text{total power dissipation} & T_{mb} = 25 \ ^{\circ}\text{C}; \ \text{see Figure 2} & - \\ \\ \text{storage temperature} & -55 \\ \\ \text{junction temperature} & -55 \\ \\ \hline \textbf{diode} & & \\ \\ \text{source current} & T_{mb} = 25 \ ^{\circ}\text{C} & - \\ \\ \text{peak source current} & T_{mb} = 25 \ ^{\circ}\text{C} & - \\ \\ pulsed; \ t_p \leq 10 \ \mu\text{s}; \ T_{mb} = 25 \ ^{\circ}\text{C} & - \\ \\ \hline \textbf{ggedness} & & \\ \\ \text{non-repetitive drain-source} & I_D = 6 \ \text{A}; \ \text{V}_{sup} \leq 55 \ \text{V}; \ \text{R}_{GS} = 50 \ \Omega; & - \\ \end{array}$	$\begin{tabular}{ c c c c } \hline T_j &\geq 25 \ {}^\circ\mbox{C}; \ T_j &\leq 175 \ {}^\circ\mbox{C} & - & 55 \\ \hline drain-gate voltage & $R_{GS} &= 20 \ k\Omega & - & 55 \\ \hline gate-source voltage & $-20$ & 20 \\ \hline drain current & $T_{mb} &= 100 \ {}^\circ\mbox{C}; \ V_{GS} &= 10 \ V; \ see \ Figure 1 & - & 13 \\ \hline $T_{mb} &= 25 \ {}^\circ\mbox{C}; \ V_{GS} &= 10 \ V; \ see \ Figure 1; & - & 18 \\ \hline see \ Figure 3 & - & 18 \\ \hline peak \ drain \ current & $T_{mb} &= 25 \ {}^\circ\mbox{C}; \ pulsed; \ t_p &\leq 10 \ \mu s; & $$11$ & - & $$73$ \\ \hline total \ power \ dissipation & $T_{mb} &= 25 \ {}^\circ\mbox{C}; \ see \ Figure 2 & - & $$51$ \\ \hline storage \ temperature & $-55$ & 175$ \\ \hline junction \ temperature & $-55$ & 175$ \\ \hline diode & $-55$ & $$175$ \\ \hline diode & $-55$ & $$175$ \\ \hline diode & $-55$ & $$175$ \\ \hline peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$18$ \\ peak \ source \ current & $$T_{mb} &= 25 \ {}^\circ\mbox{C} & $-$ & $$73$ \\ \hline ggedness & $$non-repetitive \ drain-source & $$I_D &= $6 \ A; \ V_{sup} &\leq 55 \ V; \ R_{GS} &= $50 \ \Omega; & $-$ & $$36$ \\ \hline \end{tabular}$

[1] Peak drain current is limited by chip, not package.

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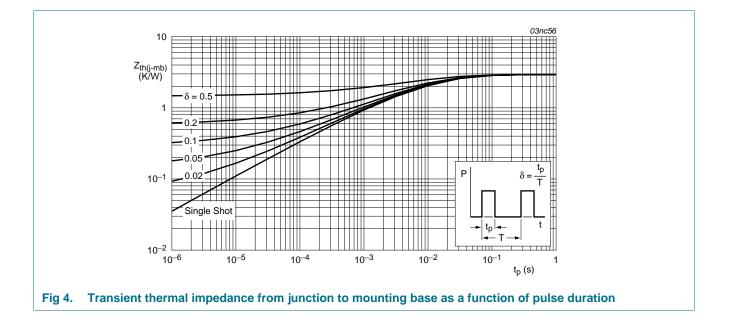
### 5. Thermal characteristics

#### Table 5.Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see <u>Figure 4</u>	-	-	2.9	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	minimum footprint; FR4 board	-	71.4	-	K/W
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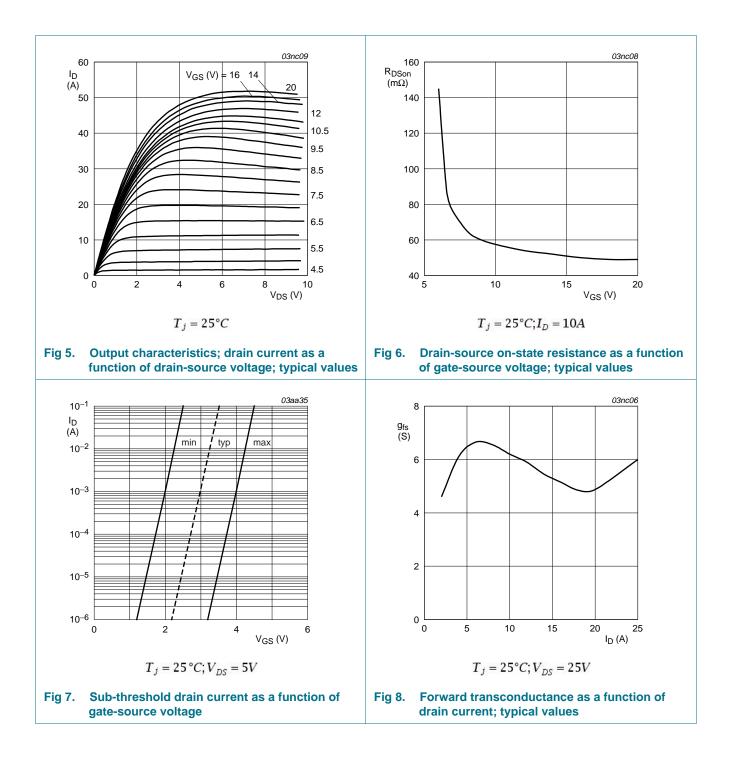


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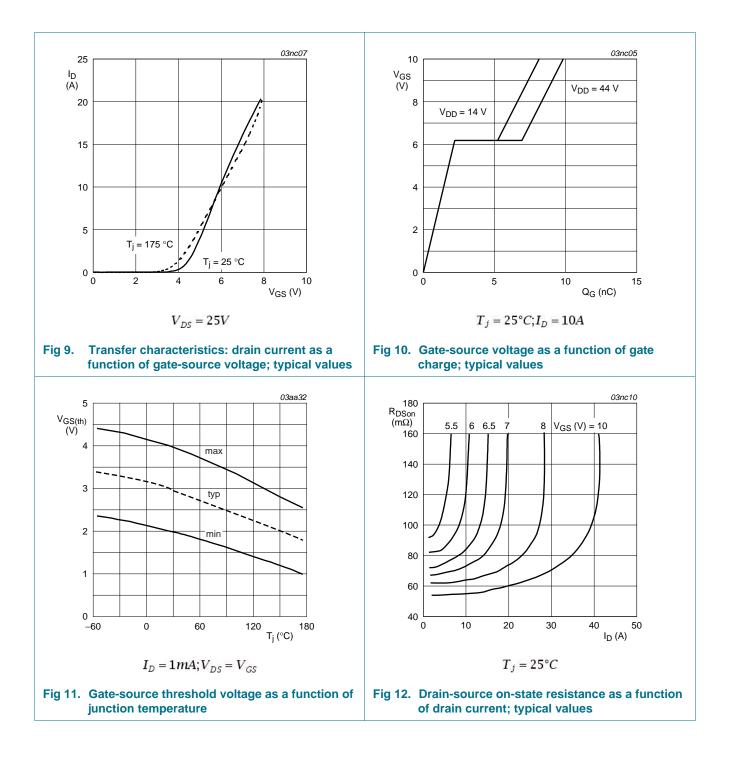
### 6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V <sub>(BR)DSS</sub>	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	55	-	-	V
breakdown voltage	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	50	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 25 °C; see <u>Figure 11</u>	2	3	4	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = -55 °C; see <u>Figure 11</u>	-	-	4.4	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 175 °C; see <u>Figure 11</u>	1	-	-	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.05	10	μA
		$V_{DS} = 55 \text{ V}; V_{GS} = 0 \text{ V}; \text{ T}_{j} = 175 \text{ °C}$	-	-	500	μA
I <sub>GSS</sub>	gate leakage current	$V_{GS}$ = 20 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
		$V_{GS} = -20 \text{ V};  V_{DS} = 0 \text{ V};  T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
R <sub>DSon</sub> drain-source on-state resistance	drain-source on-state resistance	V <sub>GS</sub> = 10 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 175 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	-	154	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C; see <u>Figure 12</u> ; see <u>Figure 13</u>	-	65	77	mΩ
Dynamic	characteristics					
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	316	422	pF
C <sub>oss</sub>	output capacitance	$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 14}{\text{Figure } 14}$	-	92	110	pF
C <sub>rss</sub>	reverse transfer capacitance		-	64	87	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; \text{ V}_{GS} = 10 \text{ V};$	-	10	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \ \Omega; T_j = 25 \ ^{\circ}C$	-	50	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	70	-	ns
t <sub>f</sub>	fall time		-	40	-	ns
L <sub>D</sub>	internal drain inductance	measured from drain lead from package to centre of die ; $T_j = 25 \text{ °C}$	-	2.5	-	nH
L <sub>S</sub>	internal source inductance	measured from source lead from package to source bond pad ; $T_j = 25 \ ^{\circ}C$	-	7.5	-	nH
Source-d	rain diode					
$V_{SD}$	source-drain voltage	I <sub>S</sub> = 10 A; V <sub>GS</sub> = 0 V; T <sub>j</sub> = 25 °C; see <u>Figure 15</u>	-	0.85	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{S} = 20 \text{ A}; \text{ dI}_{S}/\text{dt} = -100 \text{ A}/\mu\text{s};$	-	32	-	ns
Q <sub>r</sub>	recovered charge	$V_{GS}$ = -10 V; $V_{DS}$ = 30 V; $T_j$ = 25 °C	-	120	-	nC

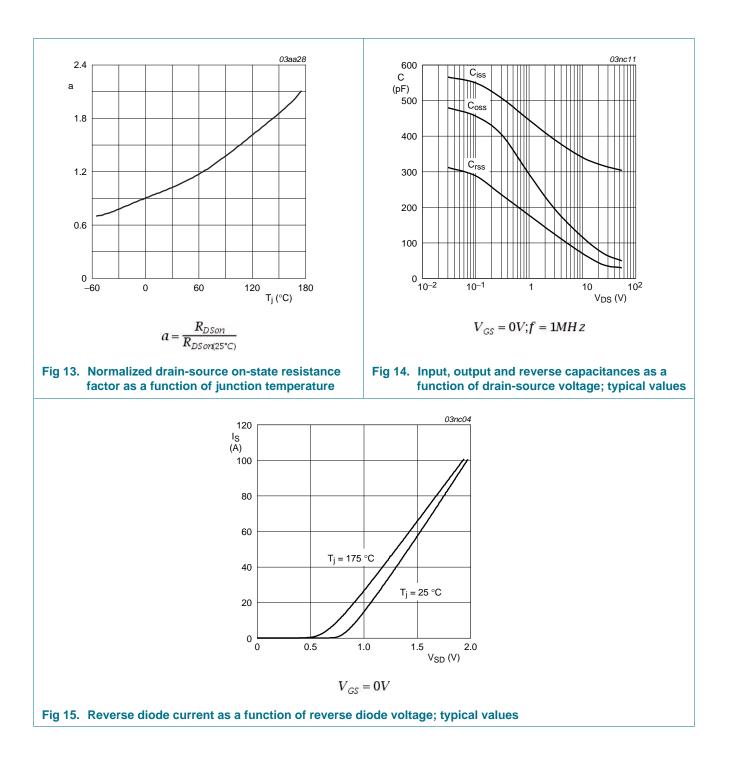
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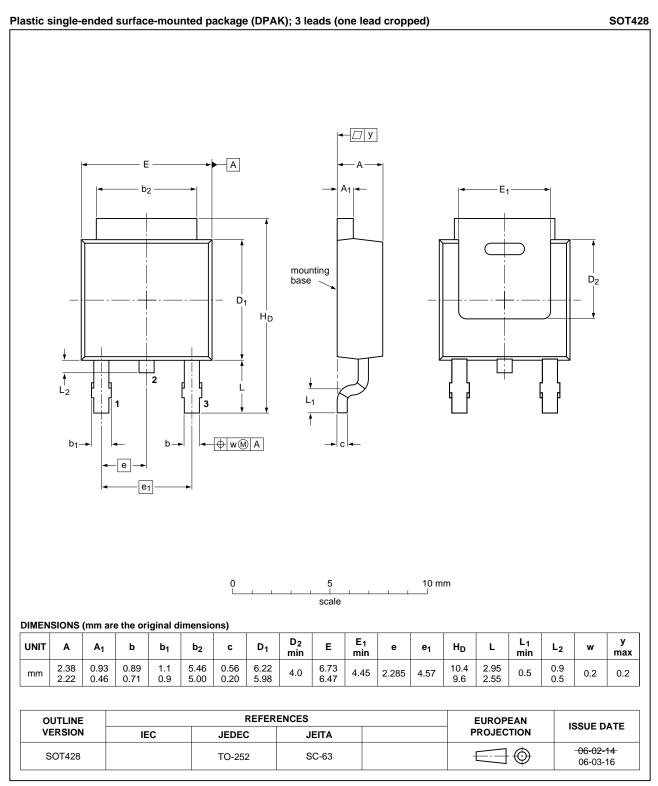
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### 7. Package outline



#### Fig 16. Package outline SOT428 (DPAK)

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### 8. Revision history

Table 7. Revision	history				
Document ID	Release date	Data sheet status	Change notice	Supersedes	
BUK7277-55A v.2	20110126	Product data sheet	-	BUK7277-55A v.1	
Modifications:	<ul> <li>The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors.</li> </ul>				
	<ul> <li>Legal texts hat</li> </ul>	ve been adapted to the new	company name where	appropriate.	
	<ul> <li>Various change</li> </ul>	les to content.			
BUK7277-55A v.1	20010201	Product specification	-	-	

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### 9. Legal information

#### 9.1 Data sheet status

Document status[1][2]	Product status <sup>[3]</sup>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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